VX-409





Features

• Frequency Range: 10 MHZ to 40 MHZ

• Previous Model: C1794

Applications

Performance Specifications

Parameter	Min	Тур	Max	Units	Condition	
Frequency Stabilities ¹						
vs. Temperature Stability (includes initial accuracy, Load±10% & Supply±5%)	-40 -30 -25 -20		+40 +30 +25 +20	ppm ppm ppm ppm	-55 +105°C -40 +85°C -20 +70°C 0 +50°C	Frequency Deviation ±85 ppm ±75 ppm ±70 ppm ±65 ppm
Initial Accuracy vs. aging / 1 year vs. aging / year (following years) vs. aging / 1 year vs. aging / year (following years)	-20 -2 -10 -3 -15		+20 +2 +10 +3 +15	ppm ppm ppm ppm ppm	@+25 C, C	ontrol Voltage @ +2.50 VDC 10 to 25 MHz 10 to 25 MHz 26 to 40 MHz 26 to 40 MHz
Supply Voltage (Vs)						
Supply voltage	4.75	5.0	5.25	VDC		
Current consumption			25	mA		
w DataSheet4H.com	RF Output					
Signal			CMOS			
Duty Cycle	40		60	%		measured at 50%
Rise\Fall time			5	ns	(10% to	90%) with 2CMOS Loads
Logic Level "0"			+0.5	V		
Logic Level "1"	+4.0			V		

Performance Specifications

Parameter	Min	Тур	Max	Units	Condition
Frequency Tuning (EFC)					
Tuning Range	+0.5		+4.5	VDC	
Linearity			+20	%	
Input Impedance			>10	kohm	
	А	bsolute	Maximu	ım Ratings	
Supply voltage (Vs)	-0.5		+6.0	VDC	
DC Input Current			50	mA	
Lead Temperature (Soldering, 10 seconds)			300	°C	
Storage temperature range	-62		+125	°C	
	Environmental Characteristics				
Sine Vibration	Mil-STD-202, Method 204, TC "D"				
Random Vibration	Mil-STD-202, Method 214 TC "I-K" (15 minutes per axis)				
Shock	Mil-STD-202, Method 213, TC "F"				
Acceleration	Mil-STD-883, Method 2001, TC "A"				
Altitude	50,000 feet minimum to deep space				
Radiation	Radiation testing is not performed, but these VCXOs have been acceptable for use in environments up to 100K rads by analysis of the components used. They are assembled with all bipolar semiconductors with the exception of the ACMOS chip used for the CMOS output which is purchased from a wafer that has been tested to a minimum of 100K rads total dose. A copy of the parts list and materials can be provided for review.				

Manufacturing Information

QUARTZ CRYSTAL

For the flight models, swept quartz shall be used in the manufacture of the crystals. For the Engineering models, non-swept quartz shall be used.

TRAVELLERS

Travellers or Process Cards are used in the manufacturing and testing of all of the 1794 Series VCXOs and are available for customer review. Copies of these Travellers can be provided with the VCXOs at time of shipment if so specified on the purchase order.

TRACEABILITY and HOMOGENEOUS MATERIAL

Option Codes 'S' & 'R' only

Manufacturing lot and date code information shall be recorded, by VCXO serial number, of every component and all materials used in the manufacture of that VCXO. Also all semiconductors used in the manufacture of any given Production Lot of VCXOs, shall be from the wafer and have the same manufacturing lot date code. A Production Lot, as defined by Vectron, is all oscillators that have been kitted and assembled as a single group. After the initial kitting and assembly, this Production Lot may be divided into multiple sublots to facilitate alignment and test capacity and may be sealed at multiple times within a 13 week window.

TEST DATA

All Test Data is recorded by VCXO serial number. Copies of this data can be provided with the VCXOs at time of shipment if so specified on the purchase order.

REWORK

All rework follows the requirements of Mil-PRF-55310 Class 'S' for Option Code 'S' and Class 'B' for Option Codes 'R', 'B' and 'C'. The only exception is the Select-At-Test components may be replaced up to four times.

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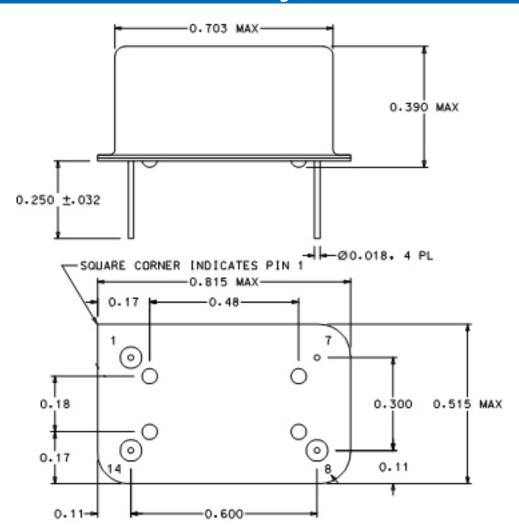
Performance Specifications

CONSTRUCTION, SCREENING & TESTING OPTIONS

NOTE: For Engineering or Prototype TCXOs requiring basic electrical testing only and no Screening, or Groups 'A' and 'B' Testing, use

the code letter 'E'.			J	, J
Operation \ Code	"S"	"R"	"C"	"B"
Design, Construction & Component Screen (see Mfging Section)	Mil-PRF-55310 Class 'S'	Mil-PRF-55310 Class 'B'	Mil-PRF-55310 Class 'B'	Mil-PRF-55310 Class 'B'
Workmanship	M883, Method 2017 for Class 'S'	M883, Method 2017 for Class 'B'	M883, Method 2017 for Class 'B'	M883, Method 2017 for Class 'B'
Screening	Mil-PRF-55310 Class 'S'	Mil-PRF-55310 Class 'S'	Mil-PRF-55310 Class 'B' modified	Mil-PRF-55310 Class 'B'
Non-Destruct Wire Bond Pull	100%	100%	N/A	N/A
Internal Visual	M883, Method 2017 for Class 'S'	M883, Method 2017 for Class 'B'	M883, Method 2017 for Class 'B'	M883, Method 2017 for Class 'B'
Stabilization Bake	48 hrs minimum @ +150°C			
Thermal Shock	M883, Method 1011, TC 'A'	M883, Method 1011, TC 'A'	N/A	N/A
Constant Acceleration	M883, Method 2001, TC 'A' (5000 gs, Y1 Axis only)	M883, Method 2001, TC 'A' (5000 gs, Y1 Axis only)	M883, Method 2001, TC 'A' (5000 gs, Y1 Axis only)	M883, Method 2001, TC 'A' (5000 gs, Y1 Axis only)
Seal Test (fine & gross)	100%	100%	100%	100%
PIND	M883, Method 2020, TC 'B'	M883, Method 2020, TC 'B'	M883, Method 2020, TC 'B'	N/A
Electrical Test Frequency, Output levels, Input Current	@ +25°C only	@ +25°C only	@ +25°C only	@ +25°C only
Burn-In (Powered with load)	+125°C for 240 hours	+125°C for 240 hours	+125°C for 160 hours	+125°C for 160 hours
Electrical Test Frequency, Output levels, Input Current	@ +25°C & Temp Extremes specifi ed in Table II	@ +25°C & Temp Extremes specifi ed in Table II	@ +25°C & Temp Extremes specifi ed in Table II	@ +25°C & Temp Extremes specified in Table II
PDA	2% applies to Input Current @ +25°C	2% applies to Input Current @ +25°C	10% applies to Input Current @ +25°C	10% applies to Input Current @ +25°C
Radiographic	M883, Method 2012	M883, Method 2012	N/A	N/A
Group 'A'	100%	100%	Sample per Mil-PRF-55310	Sample per Mil-PRF-55310
Group 'B' (30 day Aging @ +70°C)	100%	100%	Sample per Mil-PRF-55310	Sample per Mil-PRF-55310

Outline Drawing / Enclosure

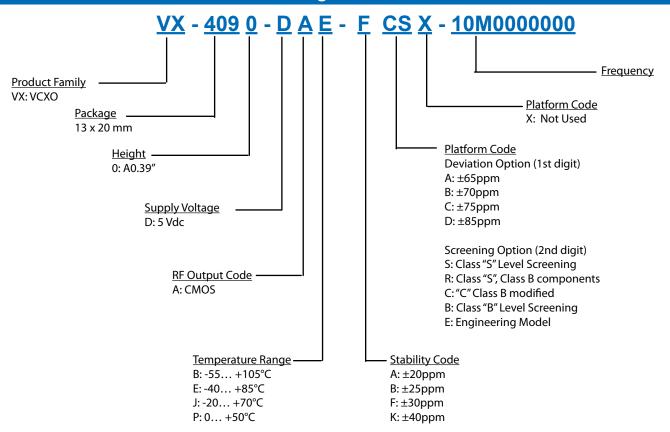


	Type A	
Code	Height "H"	Pin Length
0	0.39"	0.25"

Pin Connections				
1	Electrical Adjust (EFC)			
7	Ground (Case)			
8	RF Output			
14	Supply			

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Ordering Information



Notes:

- Contact factory for improved stabilities or additional product options. Not all options and codes are available at all frequencies.
- 2. Unless other stated all values are valid after warm-up time and refer to typical conditions for supply voltage, frequency control voltage, load, temperature (25°C).
- 3. Phase noise degrades with increasing output frequency.
- 4. Subject to technical modification.
- 5. Contact factory for availability.

For Additional Information, Please Contact USA: Asia: Europe: Vectron International Vectron International **Vectron International** 267 Lowell Road Landstrasse, D-74924 1F-2F, No 8 Workshop, No 308 Fenju Road Neckarbischofsheim, Germany Hudson, NH 03051 WaiGaoQiao Free Trade Zone www.DataSherel: 1.888.328.7661 Tel: +49 (0) 3328.4784.17 Pudong, Shanghai, China 200131 Tel: 86.21.5048.0777 Fax: +49 (0) 3328.4784.30 Fax: 1.888.329.8328 Fax: 86.21.5048.1881 Disclaimer Vectron International reserves the right to make changes to the product(s) and or information contained herein without notice. No liability is assumed as a result of their use or application. No rights under any patent accompany the sale of any such product(s) or information.